

<b>Notice of References Cited</b>	Application/Control No. 10/562,356	Applicant(s)/Patent Under Reexamination TAKASE ET AL.	
	Examiner EDMUND H. LEE	Art Unit 1791	Page 1 of 1

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*	B	US-2007/0138696	06-2007	Takase et al.	264/272.17
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	F	US-			
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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